

Notice of References Cited	Application/Control No. 10/823,364	Applicant(s)/Patent Under Reexamination SHANNON ET AL.	
	Examiner Mahmoud Dahimene	Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0127319	07-2003	Demaray et al.	204/192.26
*	B	US-2003/0148611	08-2003	Dhindsa et al.	438/689
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lieberman et al. (Plasma Sources Sci. Technol., 11 (2002) pages 283-293)
	V	Georgieva et al. (Journal of Applied Physics, V. 94, No. 6, Sept. 15 2003, pages 3748-3756). □ □
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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